

Abstract

Test switching circuit for a high speed data interface
(1) of an integrated circuit comprising switching tran-
5 sistors (T1 - T6) which switch in a test mode a termina-
tion resistor output stage (15) of a data transmission
signal path (17) to a termination resistor input stage
(18) of a data reception signal path (25) to form an in-
ternal feedback test loop within said integrated cir-
10 cuit.

(Figure 6)